

Search Terms	
1	CAPACTANCE
2	CAPACTANCES
3	COUPLING
4	COUPLINGS
5	CROSS-TALK
6	CROSS-TALKS
7	CROSTALK
8	CROSTALKS
9	DEGRADATION
10	DEGRADATIONS
11	DELAY
12	DELAYING
13	DELAYINGS
14	DELAYS
15	FREQUENCIES
16	FREQUENCY
17	FREQUENCYS
18	NOISE
19	NOISES
20	NOIZE
21	NOIZES
22	OSCILLATOR
23	REFERENCE
24	REFERENCES
25	RING
26	RINGS
27	SIGNAL
28	SIGNALS
29	SUBSTRATE
30	SUBSTRATES
31	TEST
32	TESTABLE
33	TESTED
34	TESTER
35	TESTERS
36	TESTING
37	TESTINGS
38	TESTS

	Total	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
1	252725							
2	40041							
3	1056572							
4	77789							
5	18933							
6	252							
7	31969							
8	1488							
9	327135							
10	4579							
11	591378							
12	86120							
13	7							
14	145075							
15	334848							
16	1566547							
17	52							
18	704651							
19	60346							
20	236							
21	11							
22	290076							
23	3316787							
24	326726							
25	1617390							
26	433932							
27	3438291							
28	1754339							
29	1725661							
30	381968							
31	1130633							
32	3823							
33	515473							
34	93469							
35	8517							
36	550369							
37	1057							
38	420769							

	Search Terms
39	OSCILLATORS
40	((((((((CROSS-TALK OR CROSSTALK) AND CAPACITANCE) AND (OSCILLATOR SAME RING) AND NOISE) AND (DELAYING OR DEGRADATION OR DELAY)) AND (COUPLING SAME SUBSTRATE)) AND (TESTABLE OR TESTER OR TESTED OR TESTING OR TEST)) AND (REFERENCE SAME (FREQUENCY OR SIGNAL))))

	Total	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
39	40824							
	13	3	10	0	0	0	0	
40								

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030204354 A1	20031030	20	Apparatus and method for determining effect of on-chip noise on signal propagation	702/117
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030204353 A1	20031030		Apparatus and method for determining effect of on-chip noise on signal propagation	702/117
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030204352 A1	20031030		Apparatus and method for determining effect of on-chip noise on signal propagation	702/117
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030204351 A1	20031030	20	Apparatus and method for determining effect of on-chip noise on signal propagation	702/117
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030200046 A1	20031023		Apparatus and method for determining effect of on-chip noise on signal propagation	702/117
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030151465 A1	20030814		Electronic pulse generator and oscillator	331/107SL
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030083840 A1	20030501		Apparatus and method for determining effect of on-chip noise on signal propagation	702/117
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030020544 A1	20030130		Large gain range, high linearity, low noise MOS VGA	330/254
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020180001 A1	20021205		System and method for ESD protection	257/546
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020075163 A1	20020620		Wireless spread-spectrum telesensor chip with synchronous digital architecture	340/870.16
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6759904 B2	20040706		Large gain range, high linearity, low noise MOS VGA	330/254
12	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6525609 B1	20030225		Large gain range, high linearity, low noise MOS VGA	330/254
13	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6445039 B1	20020903		System and method for ESD Protection	257/355

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			Corr, William E.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030204354	<input type="checkbox"/>
2			Corr, William E.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
3			Corr, William E.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
4			Corr, William E.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030204351	<input type="checkbox"/>
5			Corr, William E.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
6			Wood, John	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
7			Corr, William E.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
8			Behzad, Arya R.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
9			Woo, Agnes N. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
10			Smith, Stephen F. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
11	327/359		Behzad, Arya R.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
12	327/359		Behzad, Arya R.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
13	257/356, 257/357, 257/360		Woo, Agnes N. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>

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- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

- 3) Limit the results by selecting Search Options.

- 4) Click Search. See [Search Examples](#)

```
(cross-talk<or>crosstalk)
<and>noise<and>
(ring<paragraph>oscillator)
<and>
```

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(cross talk<or>crosstalk)<and>noise<and>(ring<paragr

Search

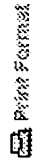
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Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

- 1 **On-chip interconnect evaluation on delay time increase by crosstalk**
Yamashita, K.; Odanaka, S.; Egashira, K.; Ueda, T.;
Electron Devices Meeting, 1999. IEDM Technical Digest. International , 5-8 Dec. 1999
Pages:631 - 634

[Abstract] [PDF Full-Text (356 KB)] IEEE CNF



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